

<b>Notice of References Cited</b>	Application/Control No. 10/510,254	Applicant(s)/Patent Under Reexamination DEKKERS ET AL.	
	Examiner Hieu P. Nguyen	Art Unit 2817	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,720,830	04-2004	Andreou et al.	330/253
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N					
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**NON-PATENT DOCUMENTS**

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